



# Development of a multichannel SiPM power supply for TAO and DUNE experiments

*Sharov Vladislav, Anfimov Nikolay, Fedoseev Dmitry, Olshevsky Alexander, Rybnikov Arseniy, Selyunin Alexander*

Supported by



Under grant #21-42-00023

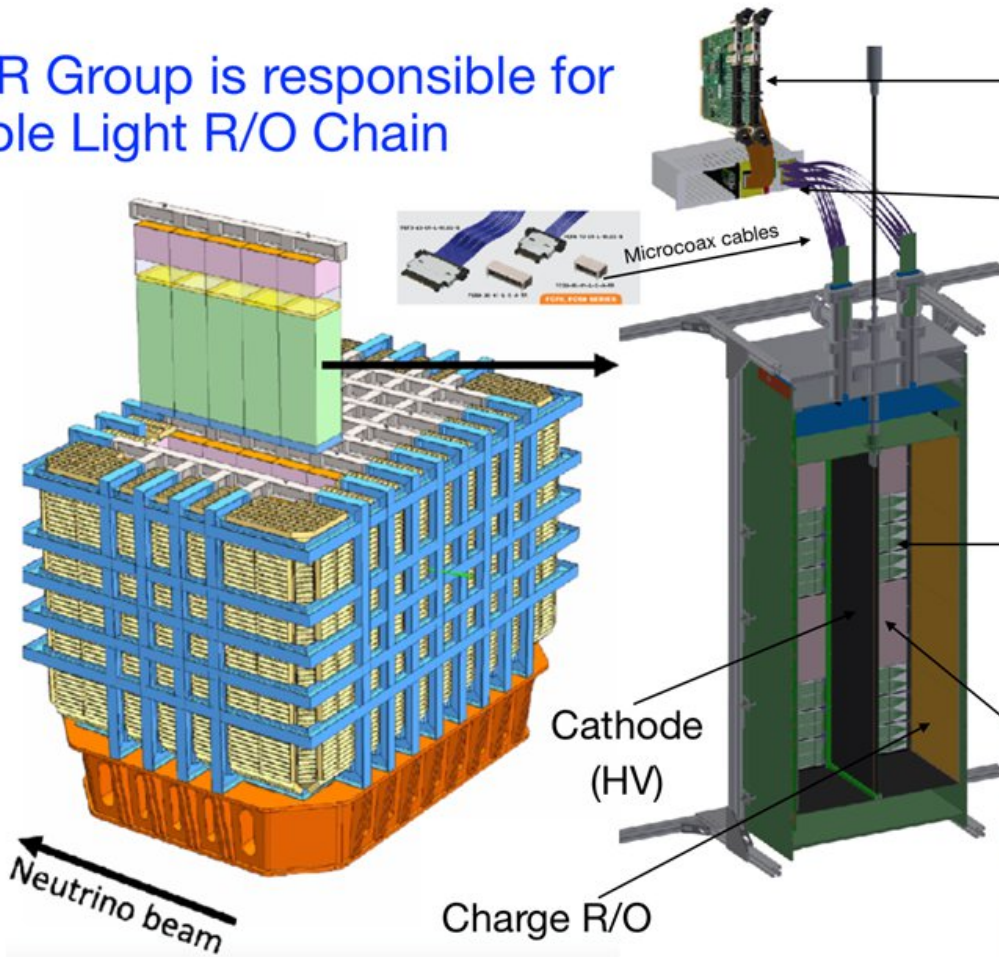
Dubna, 2021



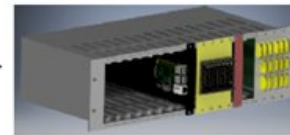
# Light R/O for LArTPC of the DUNE ND

JINR Group is responsible for whole Light R/O Chain

DUNE ND LArTPC  
7 x 5 Modules



AFI JINR ADC



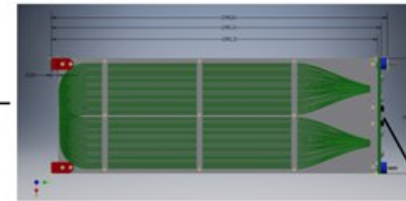
Crate with JINR Custom electronics  
SiPM power/ PGA



Slow Control Software

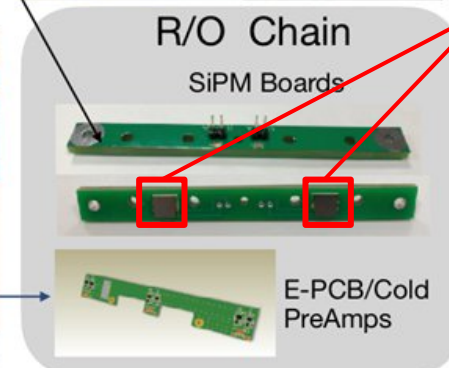
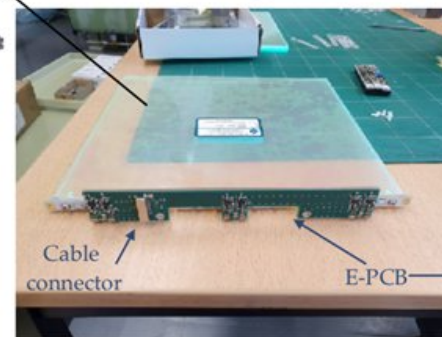
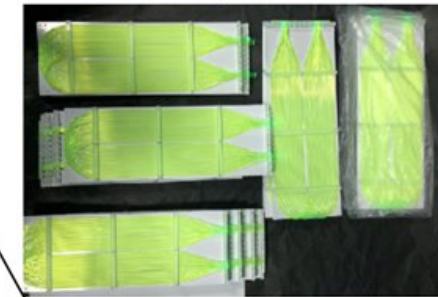
Light collection modules

LCM



ArcLight

Is in production...



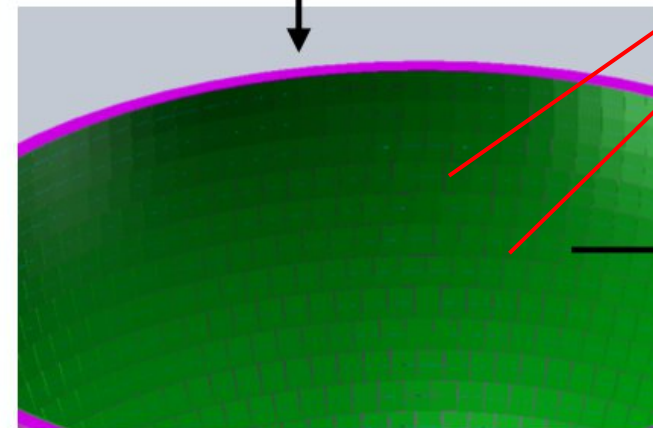
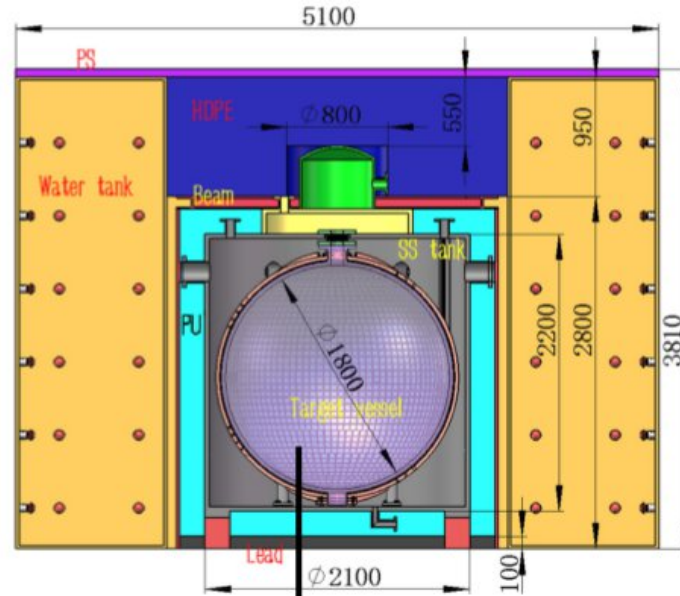
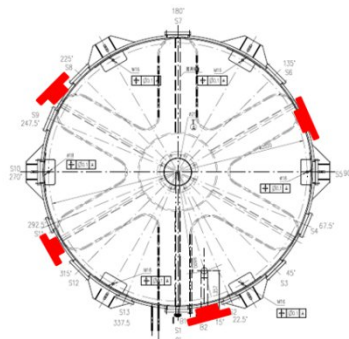
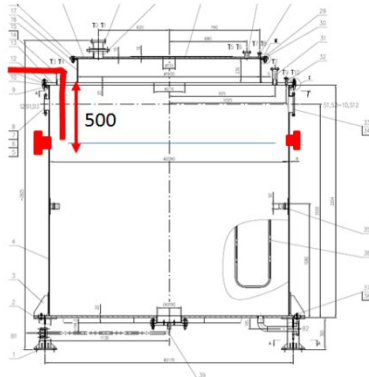
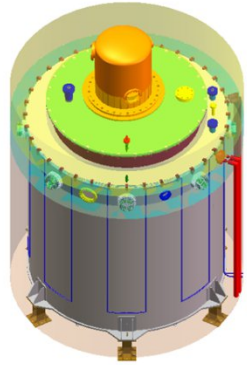
~8000 SiPMs

R/O Chain  
SiPM Boards

E-PCB/Cold  
PreAmps

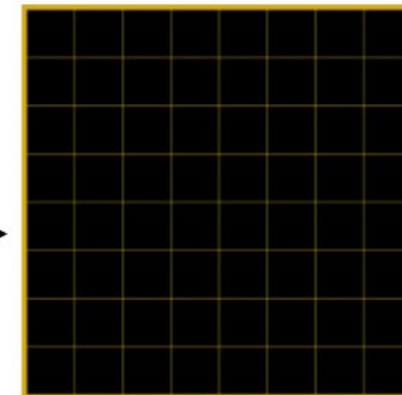
# JUNO-TAO experiment

*TAO detector*



*Sectional view of the central sphere with matrices*

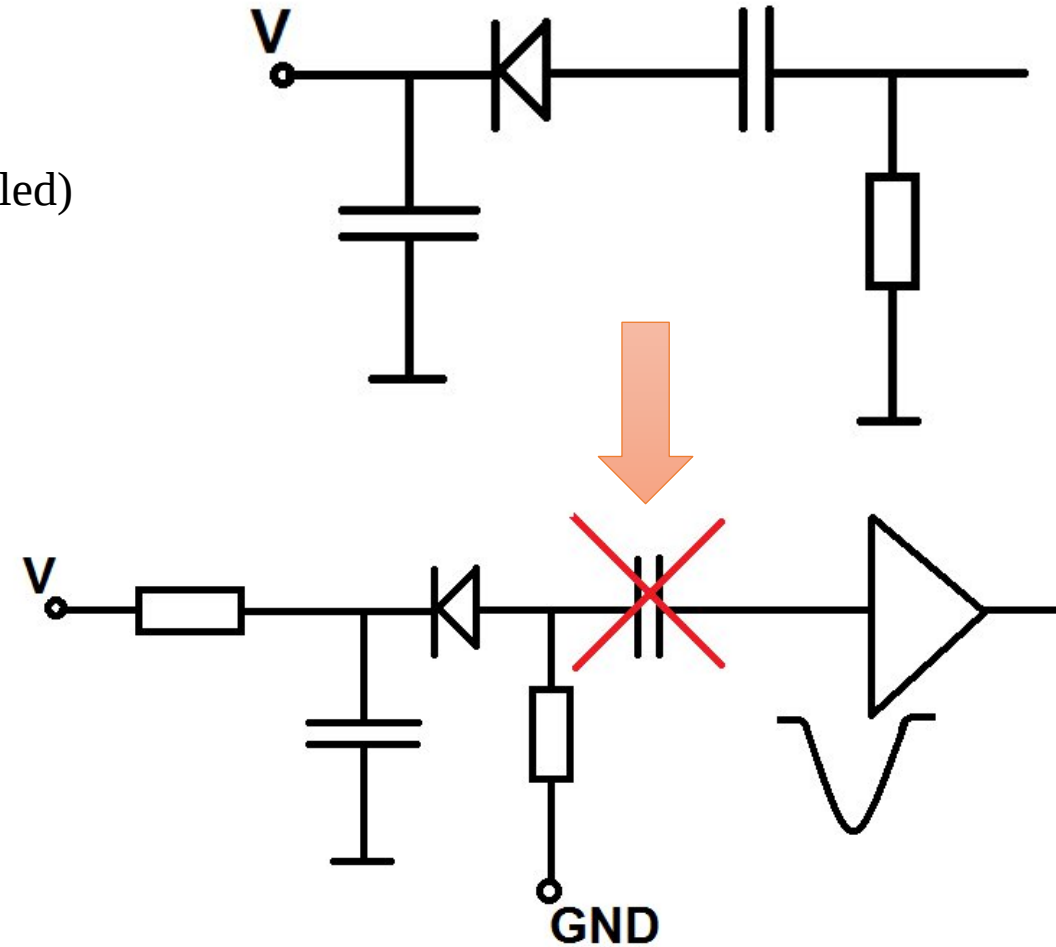
~250000 SiPMs  
~4000 arrays



*SiPMs matrix 8x8*

# Power unit requirements

1. Multichannel power supply
2. Unipolar power supply (off a channel in case of s.c; DC coupled)
3. VME 6U form factor
4. High channel density (>64 channels)
5. Setting the voltage with an accuracy of 10mV
6. Voltage stability better than 10mV
7. Reliable connection protocol : CAN
8. Configurable voltage range: 50V, 100V, 120V
9. Scaling up to thousands channels
10. Currents  $\sim 100 \mu\text{A}$  for power supply of a SiPM's arrays



# Power unit prototyping

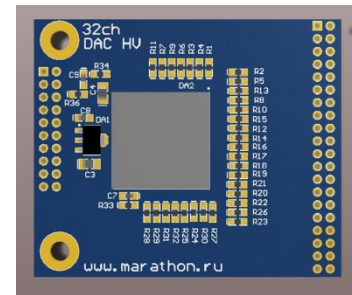
## ADC AD5535B chip

### FEATURES:

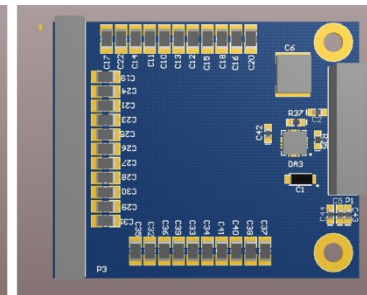
- High integration 32-channel, 14-bit denseDAC® with integrated high voltage output amplifier
- Guaranteed monotonic. Housed in 15 mm × 15 mm CSP\_BGA package
- Full-scale output voltage programmable from 50 V to 200 V via reference input
- 550  $\mu$ A drive capability
- Integrated silicon diode for temperature monitoring
- DSP-/microcontroller-compatible serial interface
- 1.2 MHz channel update rate
- Asynchronous RESET facility
- $-10^{\circ}\text{C}$  to  $+85^{\circ}\text{C}$  temperature range

## Board design

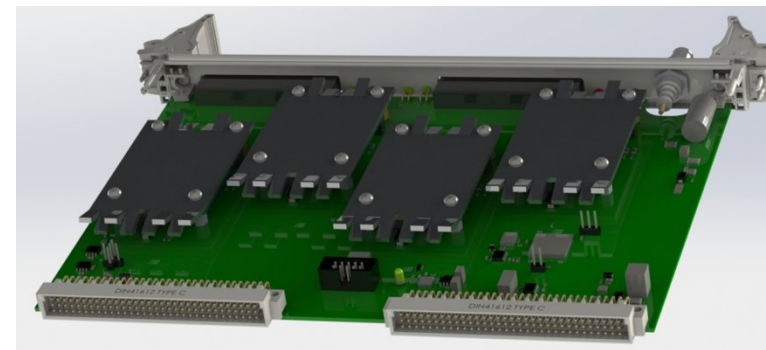
top



bottom



*DAC 32 channels*

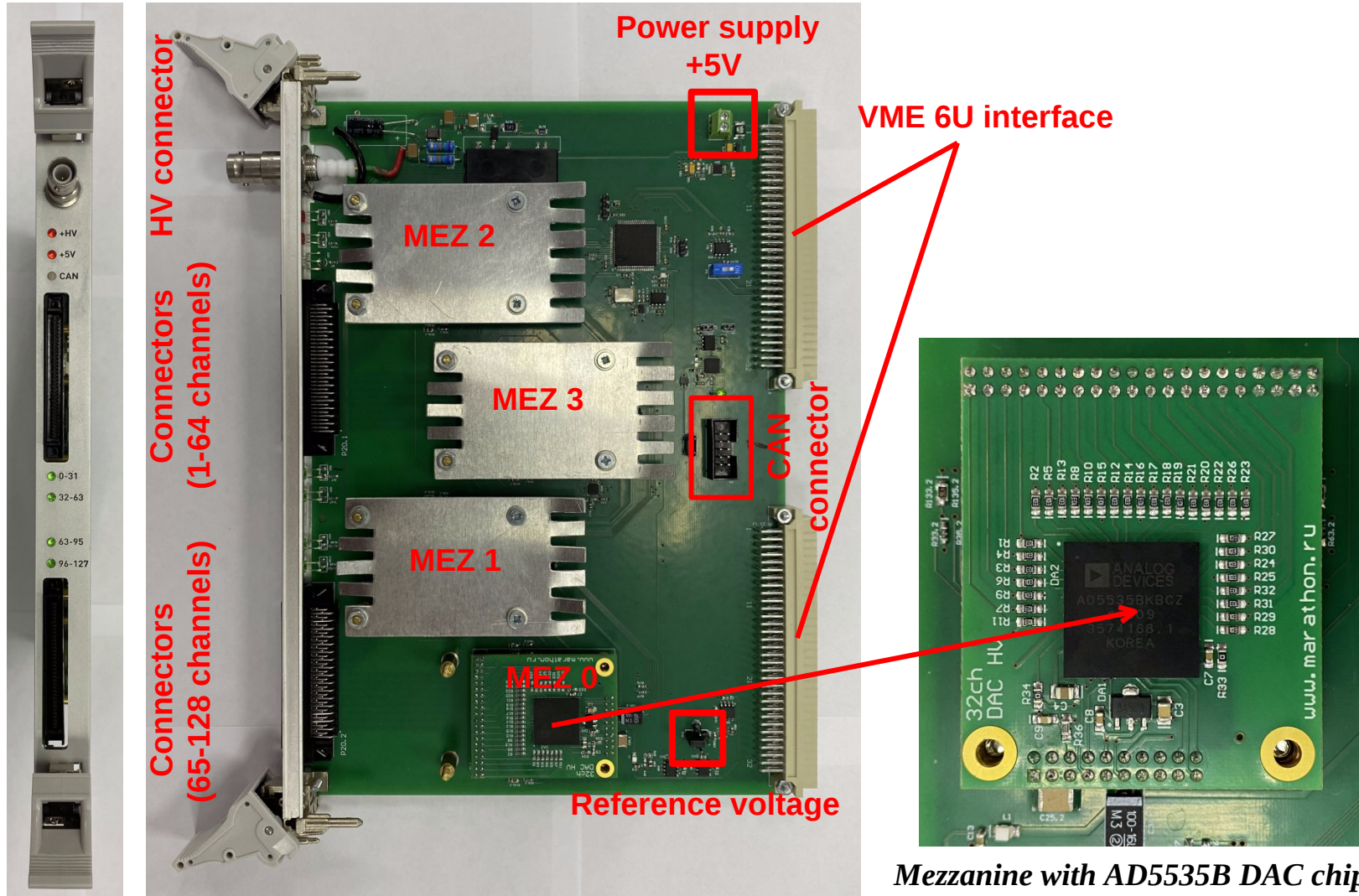


*Design by Marathon Company (MSU)*

# Pilot power unit

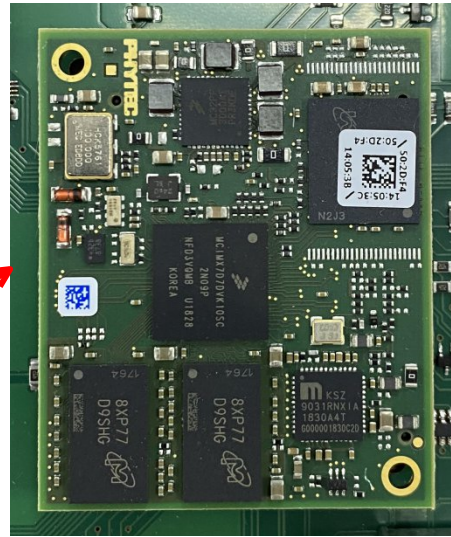
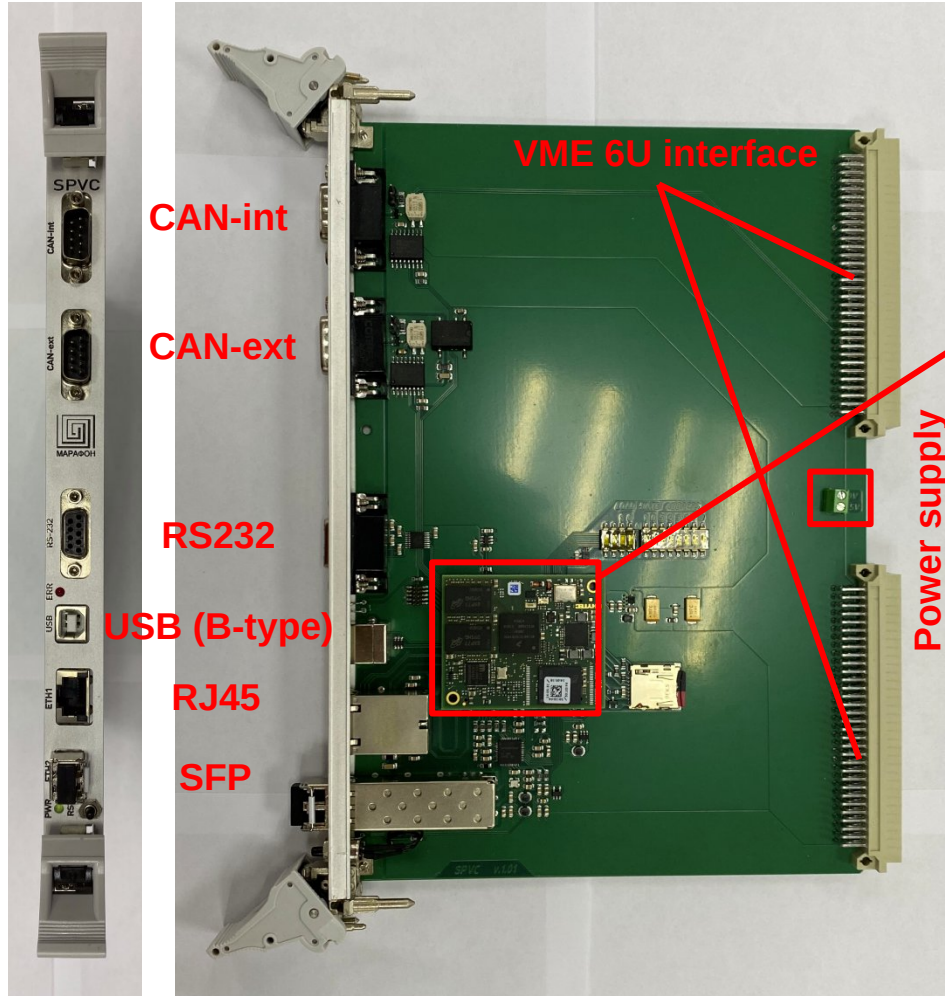
## Main Features:

- ❖ VME mechanics
- ❖ 128 channels
- ❖ Based on AD5535B chip
- ❖ Voltage up to 200 V, 14-bit
- ❖ Max current 500  $\mu$ A/ch
- ❖ 1xSHV connector
- ❖ 2x68pin IDC connectors
- ❖ PCB power supply  $\pm$ 12V, +5V by VME
- ❖ CAN-open protocol
- ❖ CAN interface on VME bus



*Mezzanine with AD5535B DAC chip*

# Pilot control unit

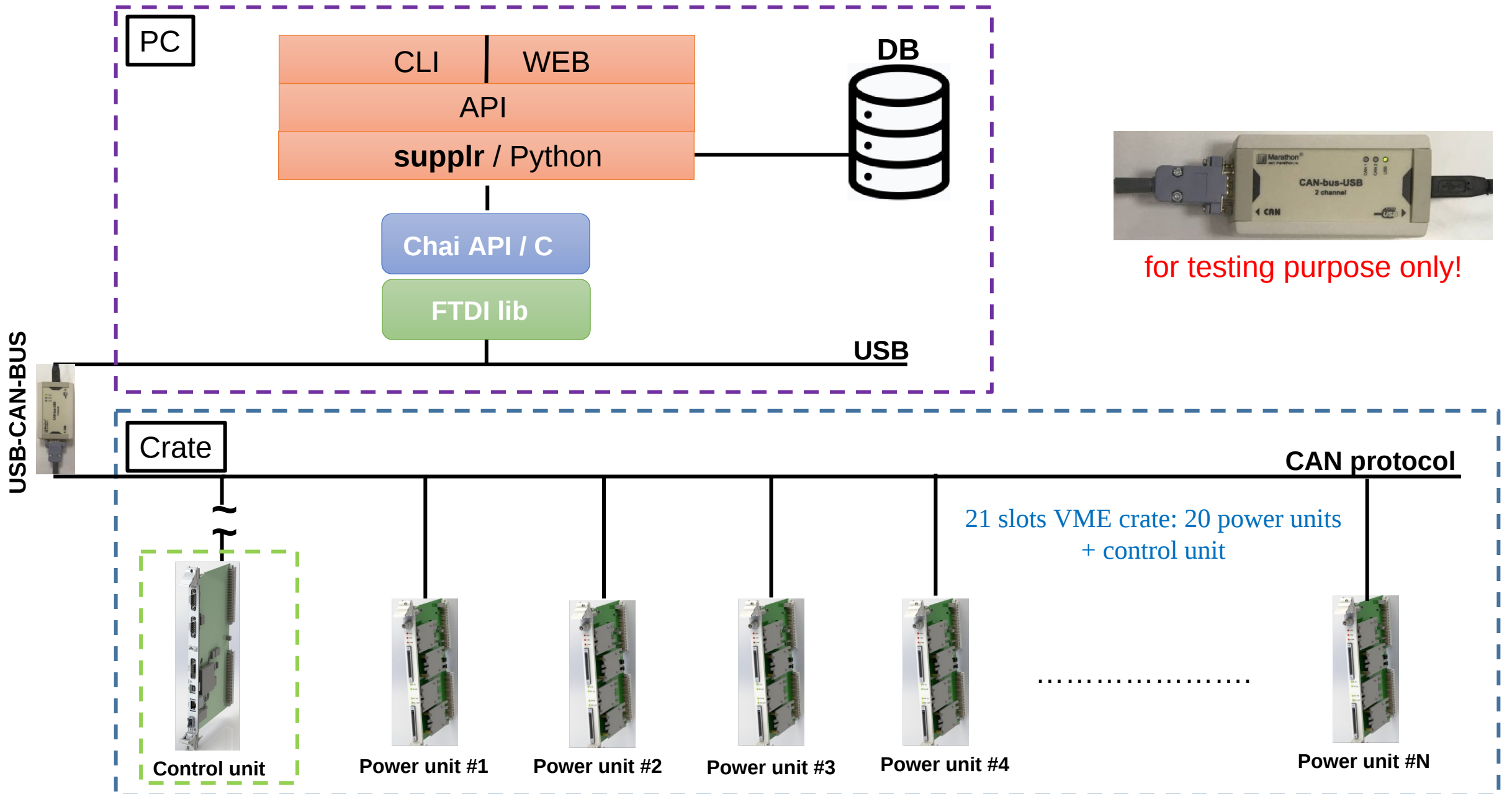


*Micro PC: phyCORE-i.MX7*

## Main Features:

- ❖ VME mechanics
- ❖ Micro PC: phyCORE-i.MX7
- ❖ CAN-int, CAN-ext
- ❖ 2x connection interfaces; 1GBPS (SFP) and 100MBPs (RJ45)
- ❖ COM port (RS232) and USB (B-type) for direct access to the micro PC
- ❖ PCB power supply  $\pm 12V$ , +5V by VME
- ❖ CAN-open protocol
- ❖ CAN interface on VME bus

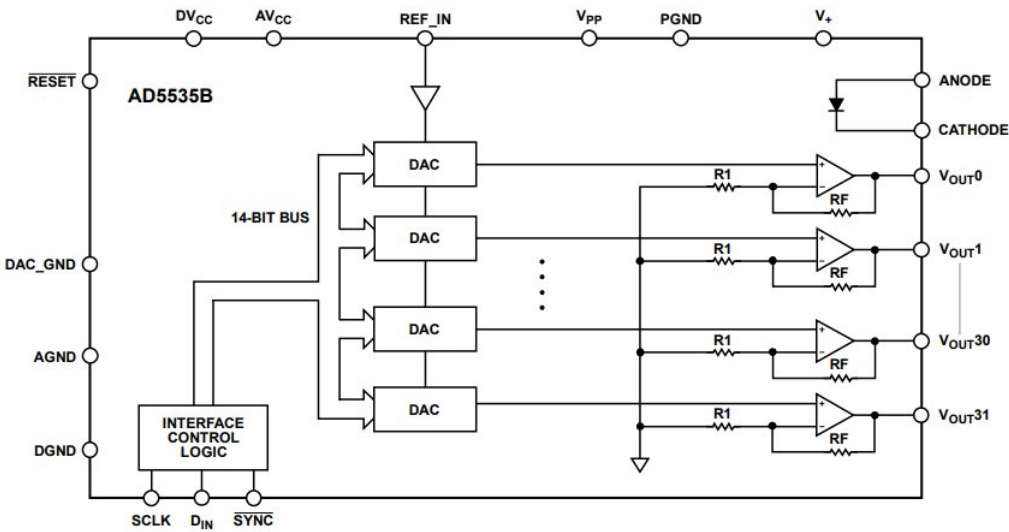
# Unit management and software



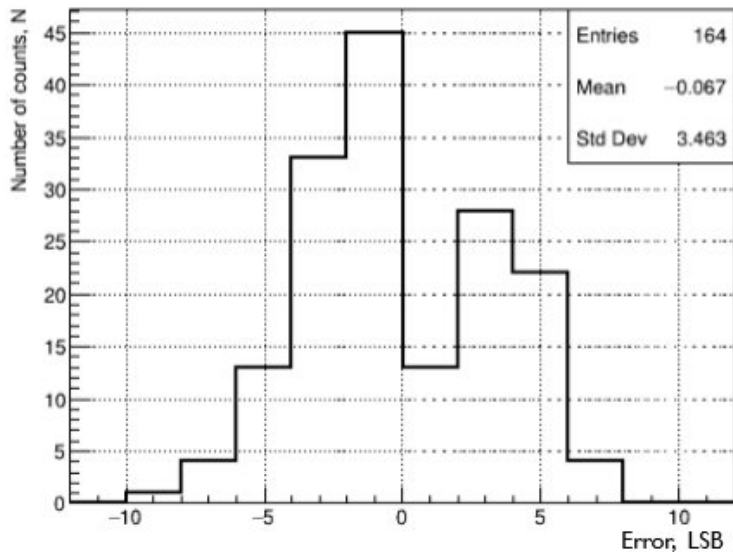
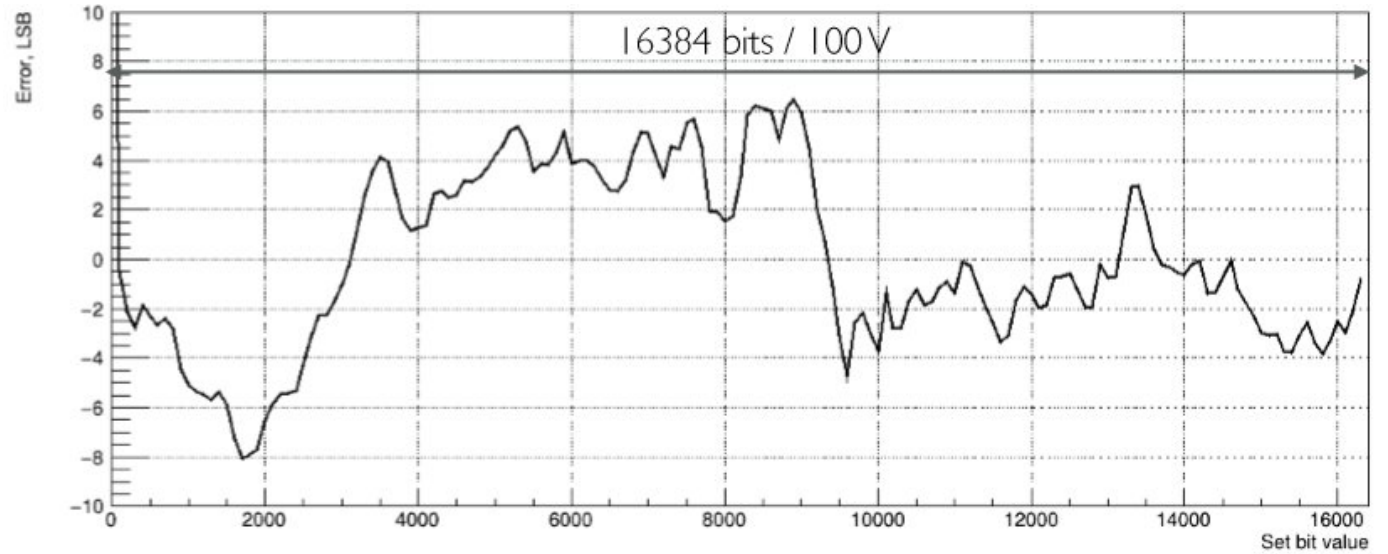


# Integral nonlinearity

## Functional block diagram of DAC



## Integral nonlinearity example for single DAC channel



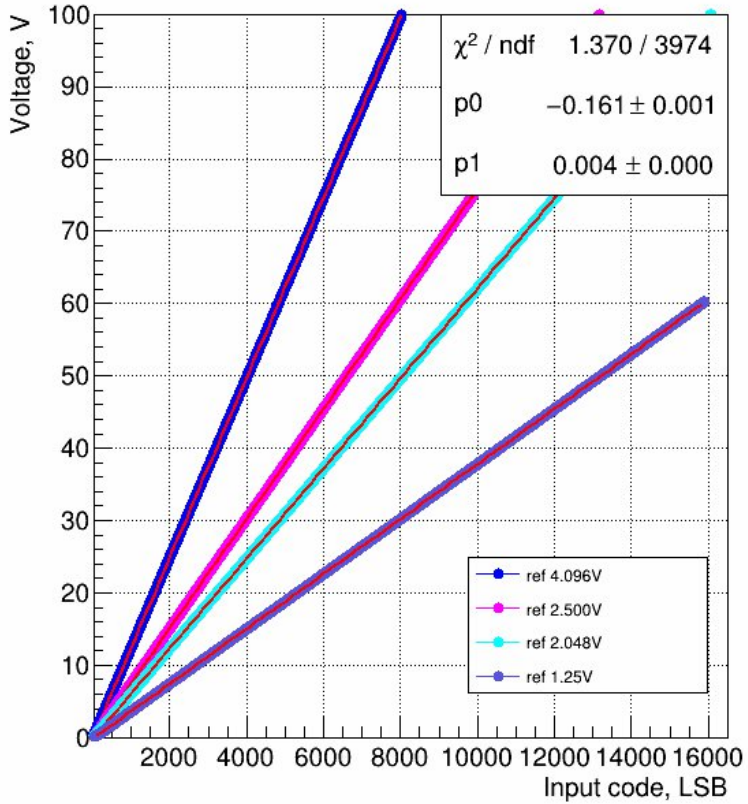
All points are within  $\pm 10$  LSB ( $\pm 60$ mV in range up to 100V)



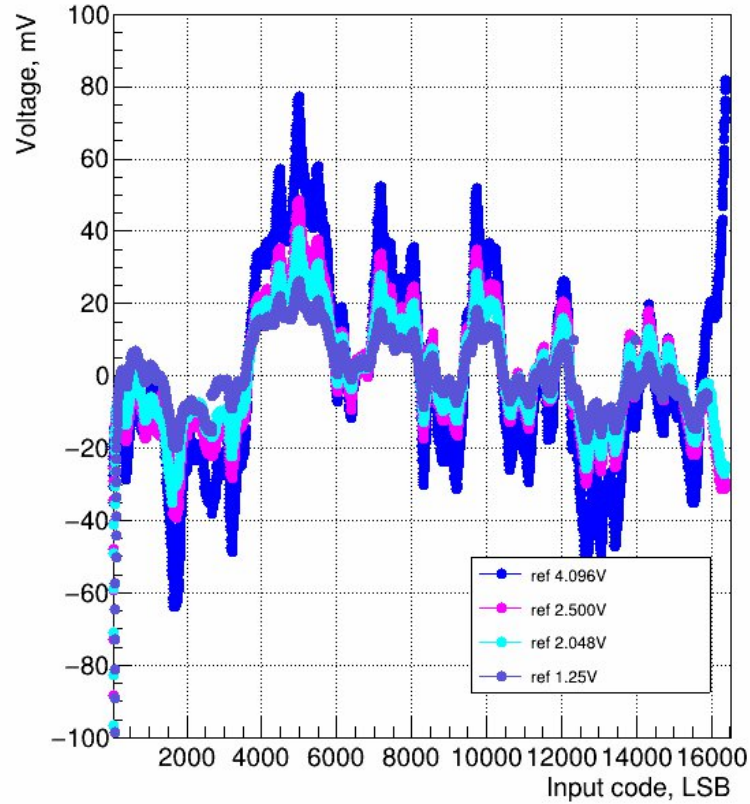
Can be corrected by calibration!

# Integral nonlinearity example for single DAC channel at different reference voltages

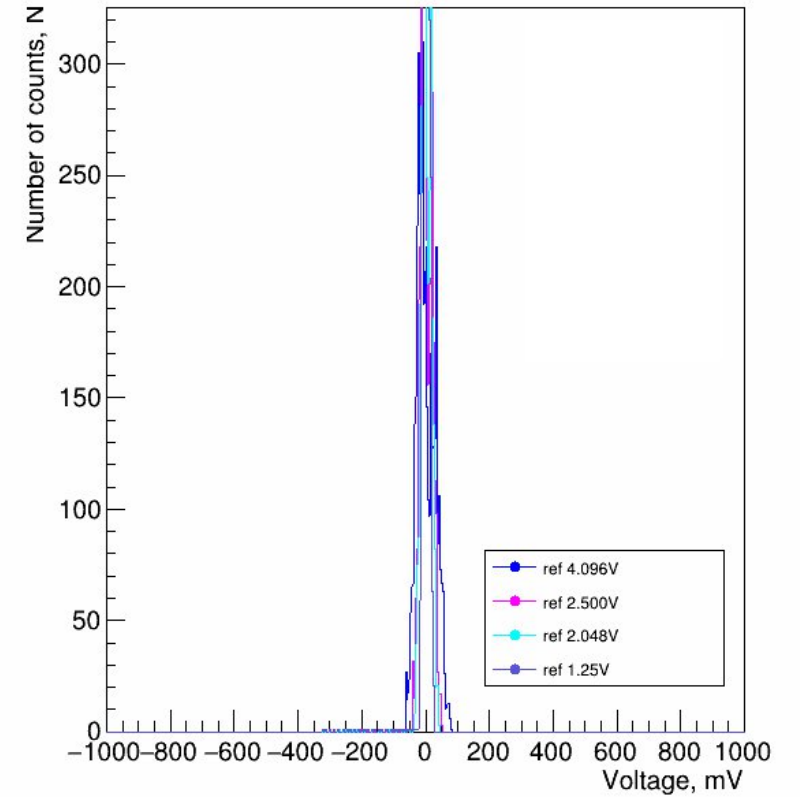
Voltage vs Input code (Keithley2000)



Integral non-linearity (Keithley2000)

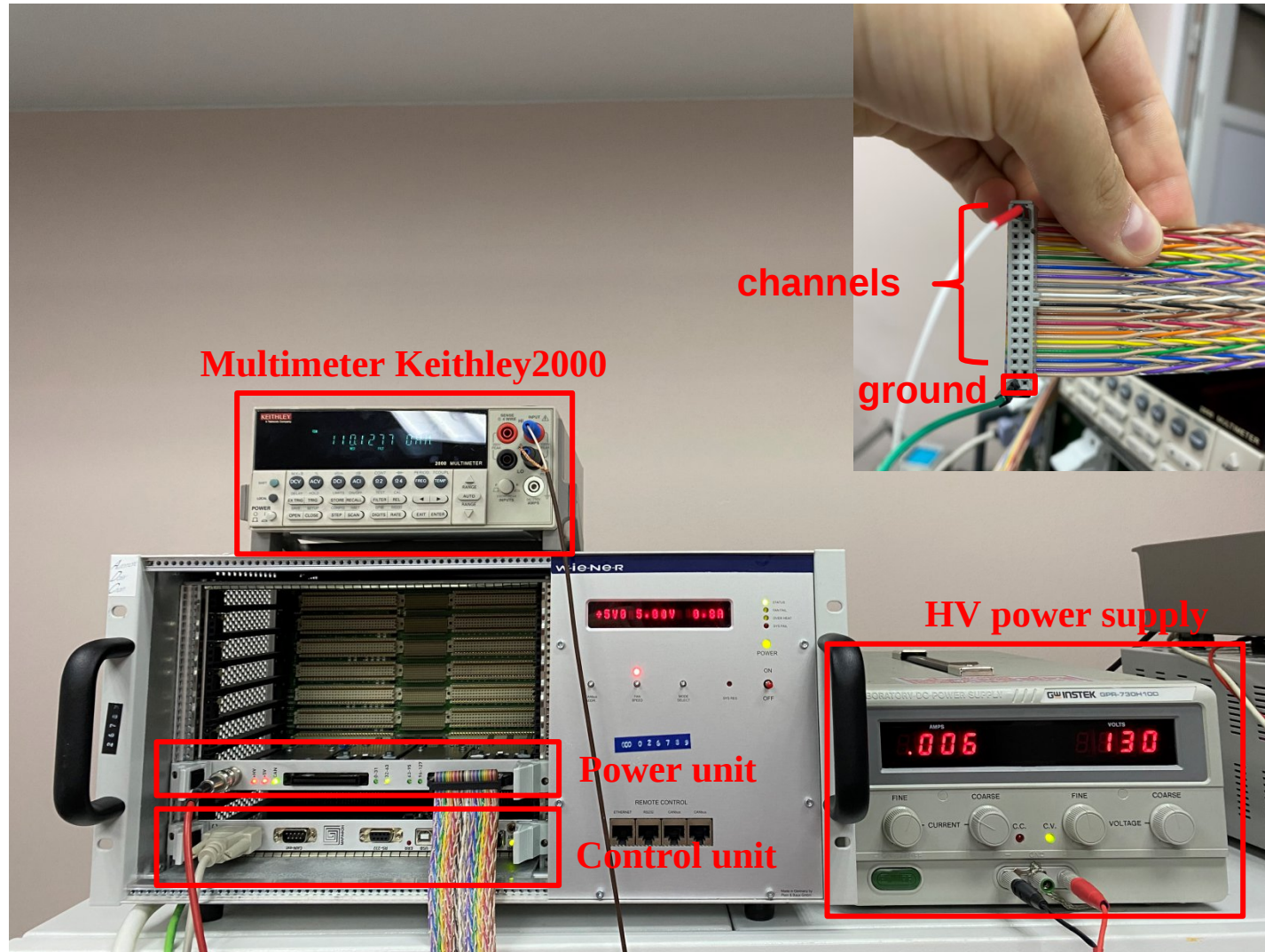


Integral non-linearity distribution (Keithley2000)



$V_{\text{ref}}, \text{V}$	Output range, V
1.25	0-50
2.048	0-100
2.5	0-150
4.096	0-200

# Calibration procedure



## The calibration procedure of a single HV channel:

1. Voltage scan over all range (0 -  $2^{14}$  bit) with an optimal step by precised multimeter.
2. Reconstruction of intermediate points.
3. Storing of all the date to a file (or database)

## Studying of optimal settings for the calibration:

1. Determination of optimal scan step (32/64/128/...)
2. Testing of algorithm for reconstruction of intermediate points

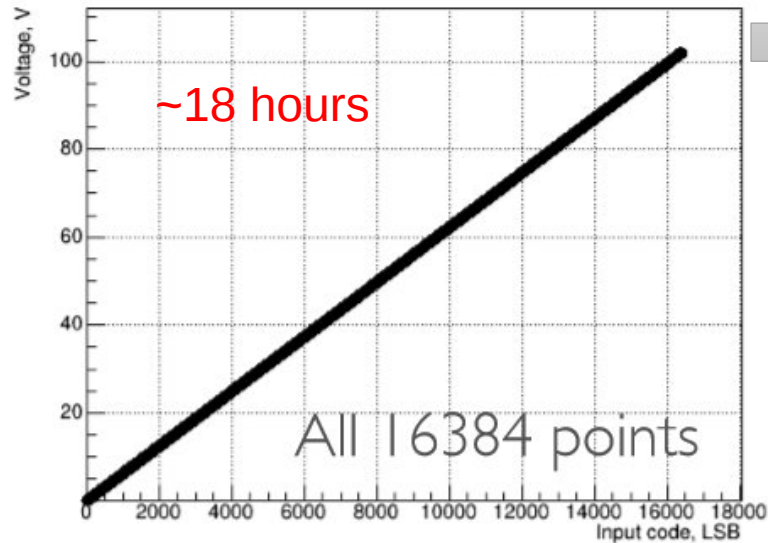
# Studying of optimal settings for the calibration

## Calibration file

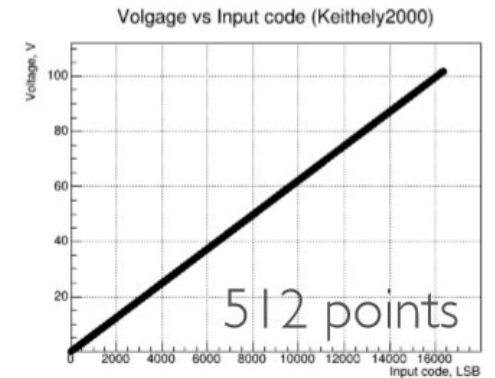
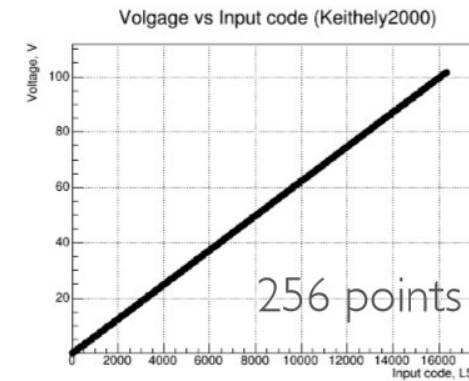
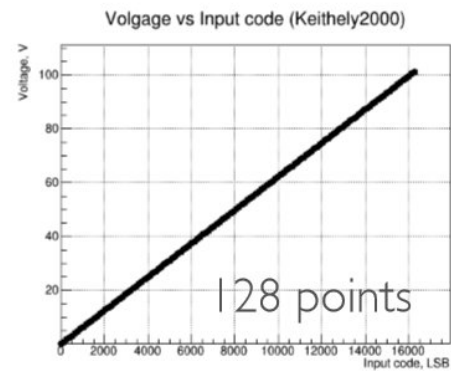
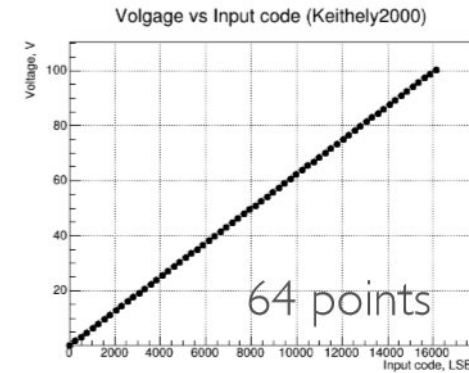
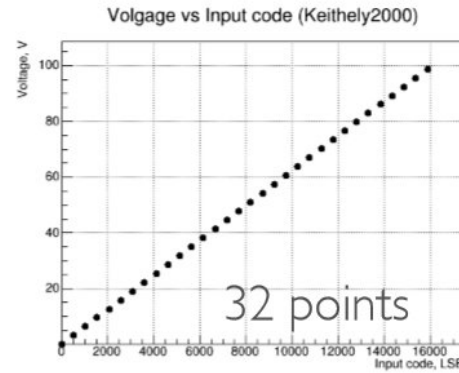
#DAC,bit	ADC,V	K2000,V	Tchip,C
0	0.122	0.198	24.669
1	0.123	0.2	24.618
2	0.125	0.201	24.636
...	...	...	...
16381	99.544	101.987	25.754
16382	99.55	101.993	25.751
16383	99.555	101.999	25.739



Voltage vs Input code (Keithely2000)



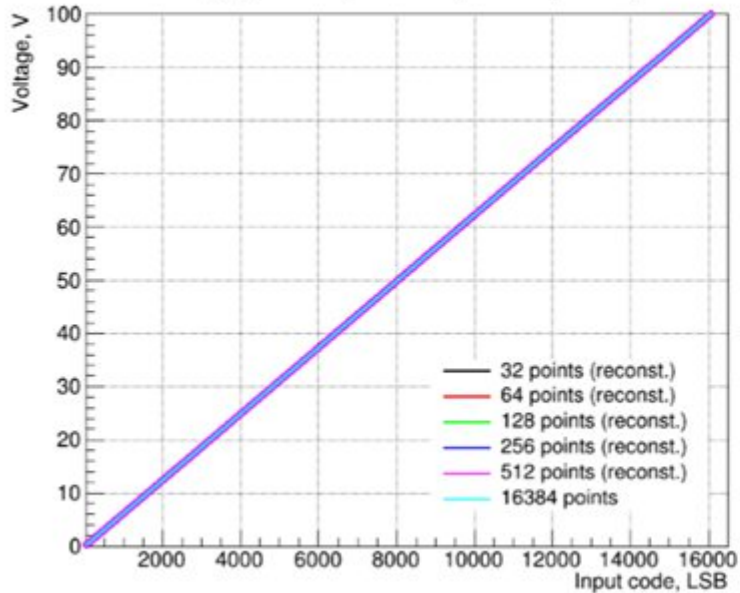
## Sampled number of points



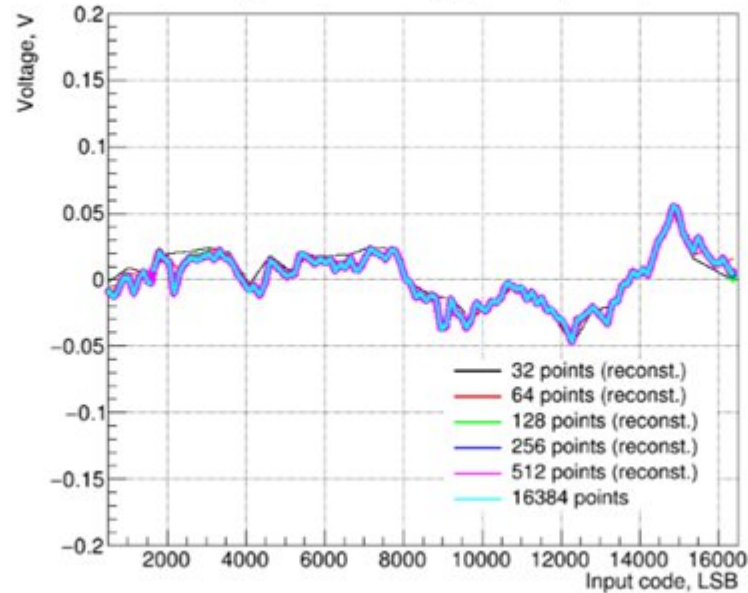
# Reconstruction (model test)

(spline algorithm)

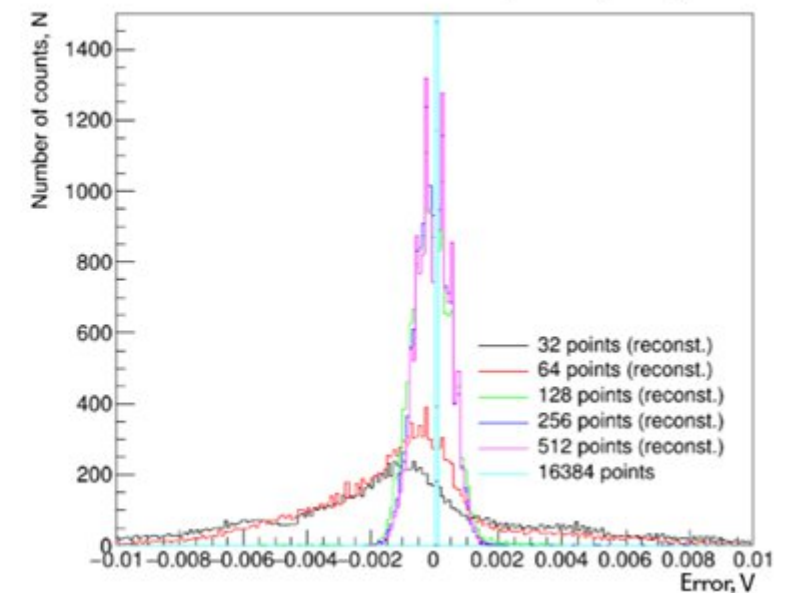
Voltage vs Input code (Keithley2000)



Integral non-linearity (Keithley2000)



Distribution of deviations (Keithley2000)



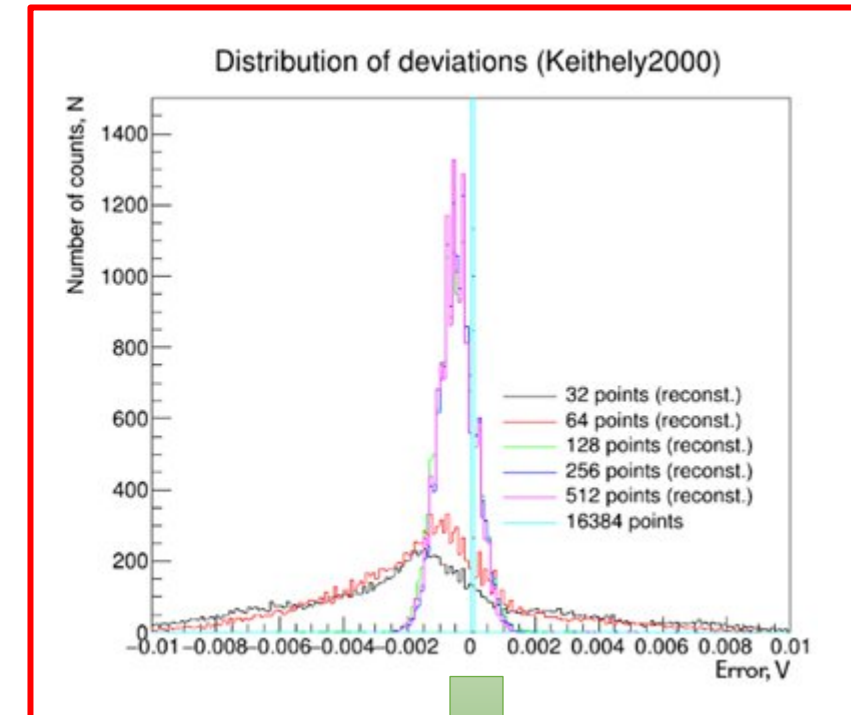
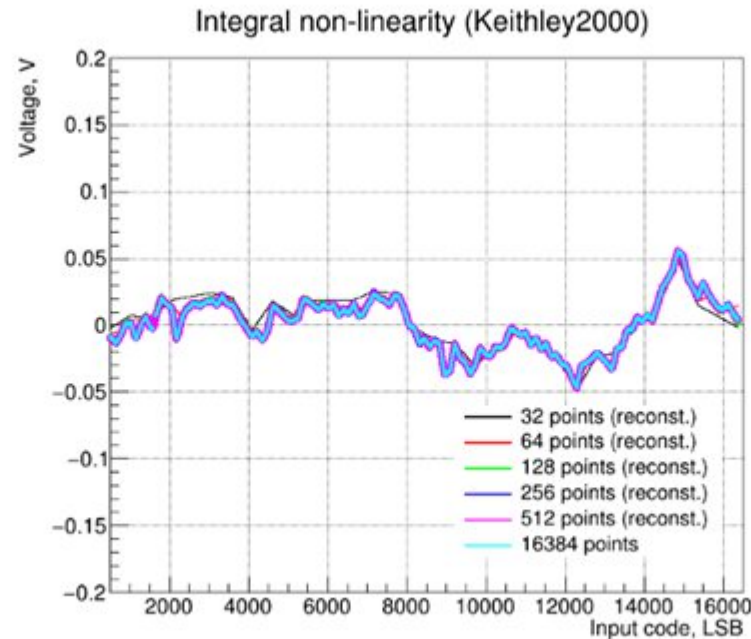
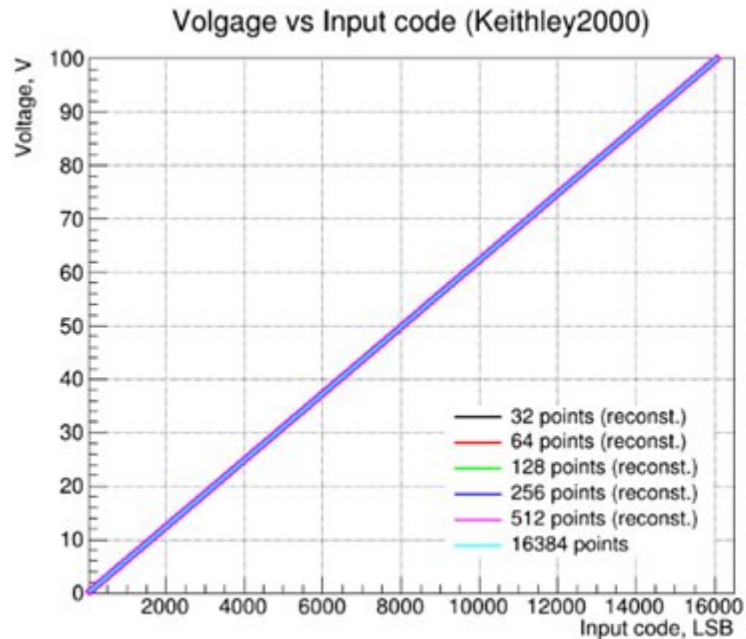
- ❖ 16384 points - original data set - measured by Keithley multimeter
- ❖ 32 points (reconst.)... - curves with the reconstructed intermediate points (also 16384 points inside)

# Reconstruction (real data)

## (spline algorithm)

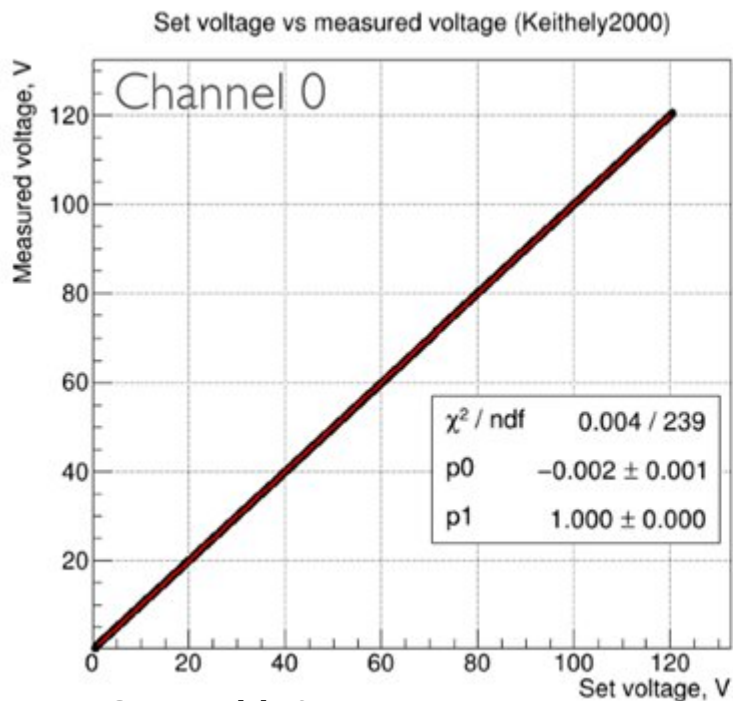
*The algorithm was applied on the real data:*

- ❖ Voltage was scanned (32, 64, 128, 256, 512 points) by means of Keithley 2000
- ❖ Intermediate points were reconstructed the same way for each set of points

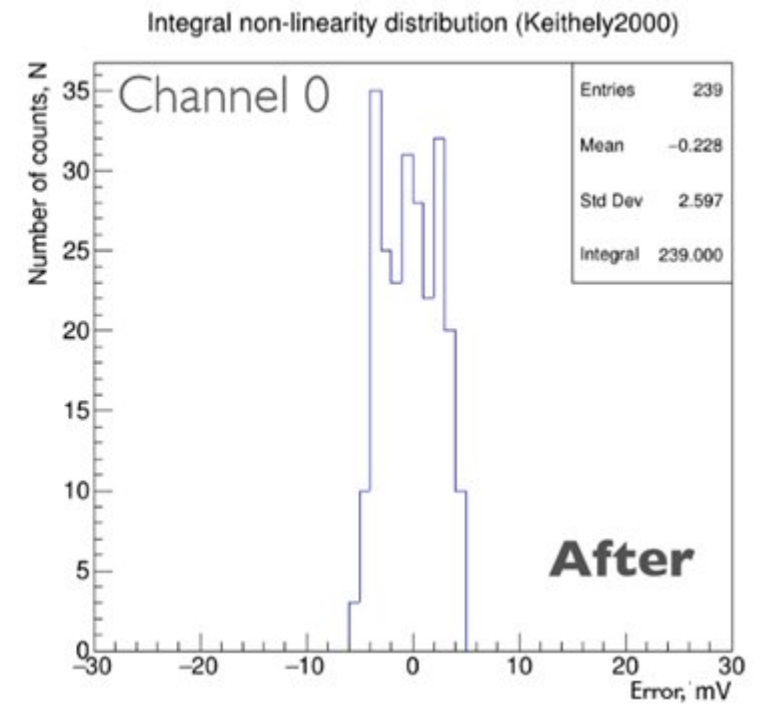
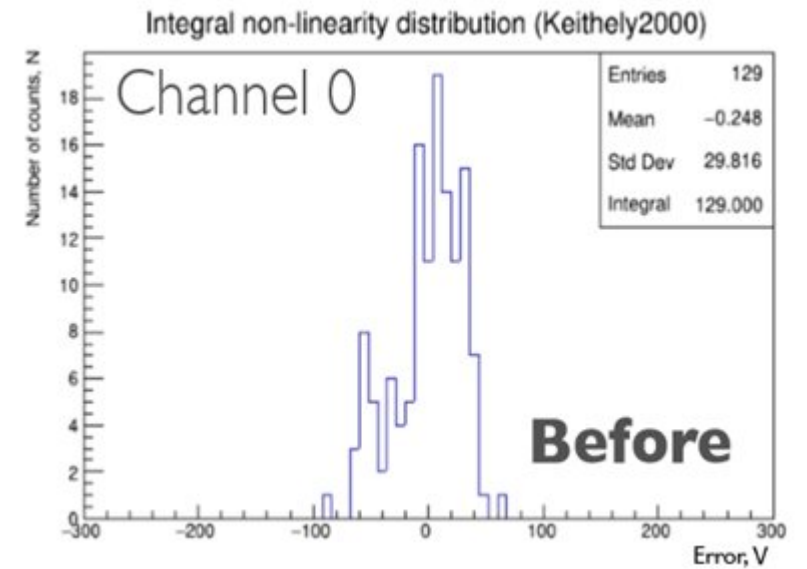
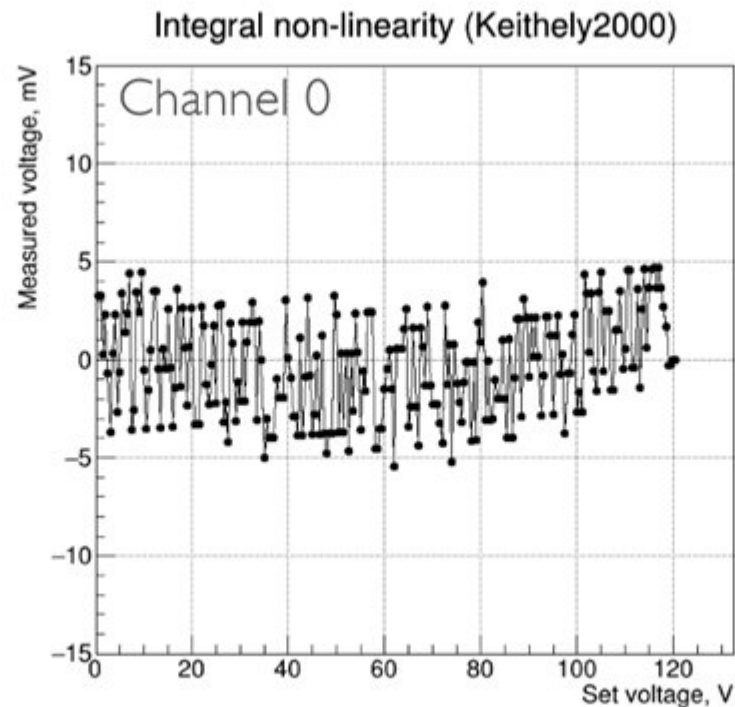


- ❖ Over 128 points must be acquired for calibration of a single channel
- ❖ time: ~10 min/128 points is required
- ❖ 128ch\*10min ~ 20h/Power Unit
- ❖ Switching channels in automatic mode is needed (multiplexer)

# Applying of correction on a single channel



Scan with 0.5V step



# Temperature stability

AD5535B chip operating range from  $-10^{\circ}\text{C}$  to  $+85^{\circ}\text{C}$

Initial temperature:  $35^{\circ}\text{C}$



$\Delta T \sim 20^{\circ}\text{C}$   $\Delta V \sim 2\text{mV}$



$\Delta T \sim 30^{\circ}\text{C}$   $\Delta V \sim 3\text{mV}$



$\Delta T \sim 40^{\circ}\text{C}$   $\Delta V \sim 5\text{mV}$

The crate and heat sinks keep the chip temperature from  $+25^{\circ}\text{C}$  to  $+30^{\circ}\text{C}$  in range from 0 to 200V



# Outstanding issues and plans

- Precise calibration photodetector use?
- QA/QC protocol
- Longevity and screening tests
- Slow control system (concept and development)
- Update from CAN to CAN-Open protocol
- Optimizing firmware and software for performance. WEB application.
- Using a control unit to monitor power units
- Simultaneous calibration of multiple power units
- Tests of power units with real detector prototypes (TAO - January-February 2022, DUNE - December)

# Summary

- The design of a control unit and a power unit with a DAC AD5535B chip has been developed
- Power supply unit management software developed
- A method for calibrating the power unit has been obtained. For a successful calibration of one channel, it is enough 128 points.
- It is necessary to use heat sinks and a ventilated crate for DAC chips. The voltage change will be less than 1 millivolt.
- The cost of one channel is 10\$, which is significant cheaper than foreign analogs.

Thank you for your attention